

Notice of References Cited

Application/Control No.

09/655,466

Applicant(s)/Patent Under
Reexamination
WU ET AL.

Examiner

Shean C Wu

Art Unit

1756

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5242618	09-1993	Krause et al.	252/299.6
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	8-209130	08-1996	JP	—	—
	O	9-255954	09-1997	JP	—	—
	P	10-45642	02-1998	JP	—	—
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&N0120=01&N2001=2&N3001=H10-045642 for English translation by Japan Patent Office
	V	http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&N0120=01&N2001=2&N3001=H08-209130 for English translation by Japan Patent Office
	W	http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&N0120=01&N2001=2&N3001=H09-255954 for English translation by Japan Patent Office
	X	

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